

AF/2825  
IFW



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re application of: Hirayanagi

Application No. 09/659,211

Filed: September 11, 2000

Confirmation No. 5080

For: ALIGNMENT-MARK DETECTION  
METHODS AND DEVICES FOR CHARGED-  
PARTICLE-BEAM MICROLITHOGRAPHY,  
AND MICROELECTRONIC-DEVICE  
MANUFACTURING METHODS  
COMPRISING SAME

Examiner: Caridad Everhart

Art Unit: 2825

Attorney Reference No. 4641-55447-01

CERTIFICATE OF MAILING

I hereby certify that this paper and the documents referred to as being attached or enclosed herewith are being deposited with the United States Postal Service as First Class Mail in an envelope addressed to:  
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ALEXANDRIA, VA 22313-1450 on the date shown below.

Attorney  
for Applicant(s)

*Paul L. Stang*

Date Mailed July 21, 2004

COMMISSIONER FOR PATENTS  
P.O. BOX 1450  
ALEXANDRIA, VA 22313-1450

**AMENDMENT AND REPLY TO FINAL ACTION**

This paper is submitted in reply to the final Office action dated April 21, 2004. It is believed that the amendments set forth herein place this application in condition for allowance.

Amendments to the Claims are reflected in the listing of claims, which begins on page 2.

Remarks begin on page 6.